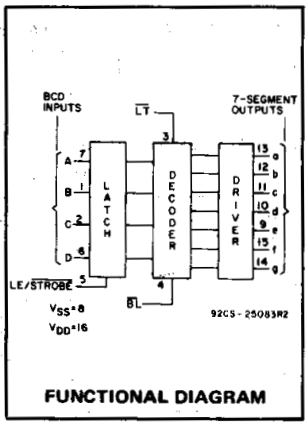
TEXAS INSTRUMENTS
Data sheet acquired from Harris Semiconductor
SCHS072A – Revised March 2002

CD4511B Types

CMOS BCD-to-7-Segment Latch Decoder Drivers

High-Voltage Types (20-Volt Rating)



FUNCTIONAL DIAGRAM

■ CD4511B types are BCD-to-7-segment latch decoder drivers constructed with CMOS logic and n-p-n bipolar transistor output devices on a single monolithic structure. These devices combine the low quiescent power dissipation and high noise immunity features of RCA CMOS with n-p-n bipolar output transistors capable of sourcing up to 25 mA. This capability allows the CD4511B types to drive LED's and other displays directly.

Lamp Test ($\overline{LT}$), Blanking ($\overline{BL}$), and Latch Enable or Strobe inputs are provided to test the display, shut off or intensity-modulate it, and store or strobe a BCD code, respectively. Several different signals may be multiplexed and displayed when external multiplexing circuitry is used. The CD4511B is supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline package (NSR suffix), and in chip form (H suffix).

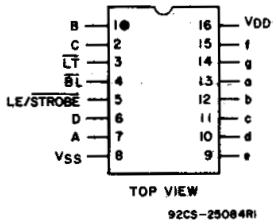
These devices are similar to the type MC14511.

Features:

- High-output-sourcing capability . . . . . up to 25 mA
- Input latches for BCD Code storage
- Lamp Test and Blanking capability
- 7-segment outputs blanked for BCD input codes > 1001
- 100% tested for quiescent current at 20 V
- Max. input current of 1 μA at 18 V, over full package-temperature range, 100 nA at 18 V and 25°C
- 5-V, 10-V, and 15-V parametric ratings

Applications:

- Driving common-cathode LED displays
- Multiplexing with common-cathode LED displays
- Driving incandescent displays
- Driving low-voltage fluorescent displays



CD4511B
TERMINAL ASSIGNMENT

MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD})
Voltages referenced to V_{SS} Terminal) . . . . . -0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS . . . . . -0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT . . . . . ±10mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = -55°C to +100°C 500mW
For T_A = +100°C to +125°C. . . . . Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW
OPERATING-TEMPERATURE RANGE (T_A) . . . . . -55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg}) . . . . . -65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max . . . . . +265°C

OPERATING CONDITIONS AT T_A = 25°C Unless Otherwise Specified

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges

Characteristic	V_{DD}	Min.	Max.	Units
Supply-Voltage Range (T_A): (Full Package-Temperature Range)	–	3	18	V
Set-Up Time (t_S)	5	150	–	ns
	10	70	–	ns
	15	40	–	ns
Hold Time (t_H)	5	0	–	ns
	10	0	–	ns
	15	0	–	ns
Strobe Pulse Width (t_W)	5	400	–	ns
	10	160	–	ns
	15	100	–	ns

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	TEST CONDITIONS				LIMITS AT INDICATED TEMPERATURES (°C)							Units
	I_{OH} (mA)	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	+25 Min.	+25 Typ.	+25 Max.	
Quiescent Device Current: I_{DD} Max.	–	–	–	5	5	5	150	150	–	0.04	5	μA
	–	–	–	10	10	10	300	300	–	0.04	10	
	–	–	–	15	20	20	600	600	–	0.04	20	
	–	–	–	20	100	100	3000	3000	–	0.08	100	
Output Voltage: Low-Level V_{OL} Max.	–	–	0,5	5	0.05				–	0	0.05	V
	–	–	0,10	10	0.05				–	0	0.05	
	–	–	0,15	15	0.05				–	0	0.05	
High-Level V_{OH} Min.	–	–	0,5	5	4	4	4.2	4.2	4.1	4.55	–	V
	–	–	0,10	10	9	9	9.2	9.2	9.1	9.55	–	
	–	–	0,15	15	14	14	14.2	14.2	14.1	14.55	–	
Input Low Voltage, V_{IL} Max.	–	0.5,3.8		5	1.5				–	–	1.5	V
	–	1,8.8	–	10	3				–	–	3	
	–	1.5,13.8		15	4				–	–	4	
Input High Voltage, V_{IH} Min.	–	0.5,3.8		5	3.5				3.5	–	–	V
	–	1,8.8		10	7				7	–	–	
	–	1.5,13.8		15	11				11	–	–	
Output Drive Voltage: High Level V_{OH} Min.	0			5	4.0	4.0	4.20	4.20	4.10	4.55	–	V
	5						–	–	–	4.25	–	
	10				3.80	3.80	3.90	3.90	3.90	4.10	–	
	15					–	3.50	3.50	–	3.95	–	
	20				3.55	3.55	3.30	–	3.40	3.75	–	
	25				3.40	3.40	–	–	3.10	3.55	–	
	0			10	9.0	9.0	9.20	9.20	9.10	9.55	–	V
	5					–	–	–	–	9.25	–	
	10	–	–		8.85	8.85	9.00	9.00	9.00	9.15	–	
	15	–	–		–	–	–	–	–	9.05	–	
	20	–	–		8.70	8.70	8.40	8.40	8.60	8.90	–	
	25	–	–		8.60	8.60	–	–	8.30	8.75	–	
	0	–	–	15	14.0	14.0	14.20	14.20	14.10	14.55	–	V
	5	–	–		–	–	–	–	–	14.30	–	
	10	–	–		13.90	13.90	14.0	14.0	14.0	14.20	–	
	15	–	–		–	–	–	–	–	14.10	–	
	20	–	–		13.75	13.75	13.50	13.50	13.70	13.95	–	
	25	–	–		13.65	13.65	–	–	13.50	13.80	–	
Output Low (Sink) Current, I_{OL} Min.	–	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	–	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	–	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Input Current, I_{IN} Max.	–	0,18	0,18	18	±0.1	±0.1	±1	±1	–	$±10^{-5}$	±0.1	μA

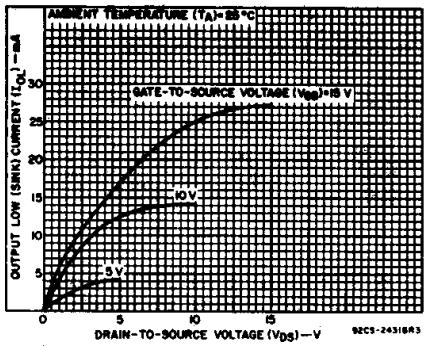


Fig. 1 – Typical output low (sink) current characteristics.

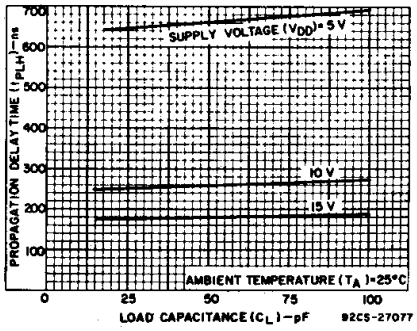


Fig. 2 – Typical data-to-output, low-to-high-level propagation delay time as a function of load capacitance.

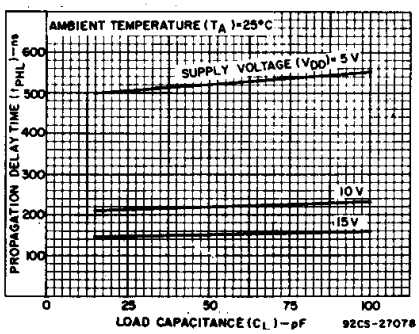


Fig. 3 – Typical data-to-output, high-to-low-level propagation delay time as a function of load capacitance.

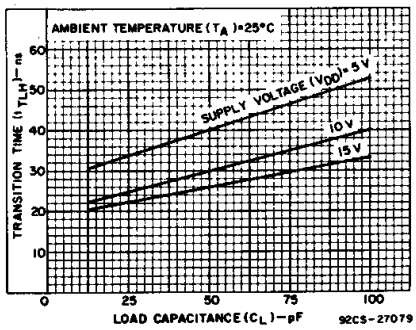


Fig. 4 – Typical low-to-high-level transition time as a function of load capacitance.

DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25°C, Input t_r, t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ

CHARACTERISTIC	Test Conditions	LIMITS All Packages			UNITS
	V_{DD} Volts	Min.	Typ.	Max.	
Propagation Delay Time: (Data) High-to-Low Level, t_{PHL}	5	–	520	1040	ns
	10	–	210	420	
	15	–	150	300	
Low-to-High Level, t_{PLH}	5	–	660	1320	ns
	10	–	260	520	
	15	–	180	360	
Propagation Delay Time: ($\overline{BL}$) High-to-Low Level, t_{PHL}	5	–	350	700	ns
	10	–	175	350	
	15	–	125	250	
Low-to-High Level, t_{PLH}	5	–	400	800	ns
	10	–	175	350	
	15	–	150	300	
Propagation Delay Time: ($\overline{LT}$) High-to-Low Level, t_{PHL}	5	–	250	500	ns
	10	–	125	250	
	15	–	85	170	
Low-to-High Level, t_{PLH}	5	–	150	300	ns
	10	–	75	150	
	15	–	50	100	
Transition Time: Low-to-High Level, t_{TLH}	5	–	40	80	ns
	10	–	30	60	
	15	–	25	50	
High-to-Low Level, t_{THL}	5	–	125	310	ns
	10	–	75	185	
	15	–	65	160	
Minimum Set-Up Time, t_S	5	150	75	–	ns
	10	70	35	–	
	15	40	20	–	
Minimum Hold Time, t_H	5	0	−75	–	ns
	10	0	−35	–	
	15	0	−20	–	
Strobe Pulse Width, t_W	5	400	200	–	ns
	10	160	80	–	
	15	100	50		
Input Capacitance, C_{IN}		–	5	7.5	pF

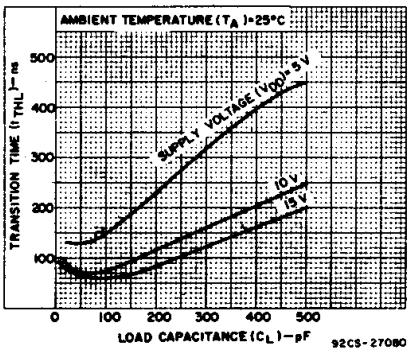


Fig. 5 – Typical high-to-low transition time as a function of load capacitance.

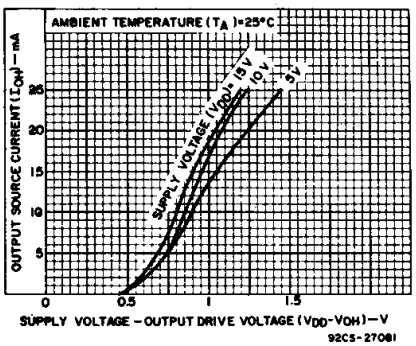


Fig. 6 – Typical voltage drop (V_{DD} to output) vs. output source current as a function of supply.

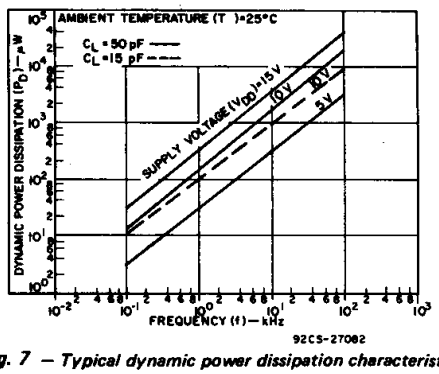


Fig. 7 – Typical dynamic power dissipation characteristics.

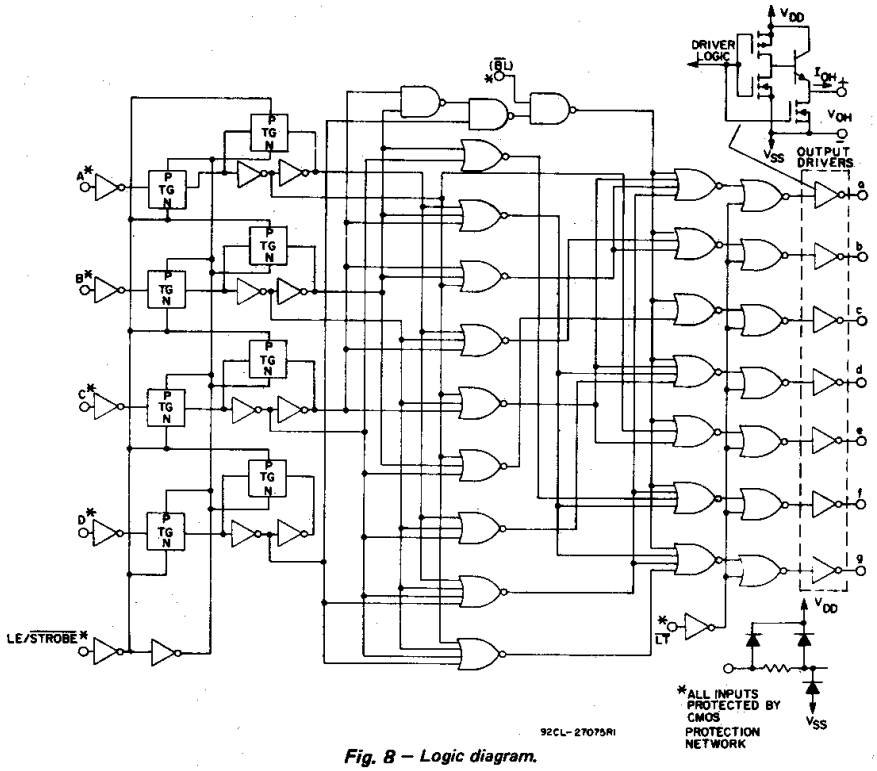


Fig. 8 – Logic diagram.

TRUTH TABLE

LE	$\overline{BI}$	$\overline{LT}$	D	C	B	A	a	b	c	d	e	f	g	Display
X	X	0	X	X	X	X	1	1	1	1	1	1	1	8
X	0	1	X	X	X	X	0	0	0	0	0	0	0	Blank
0	1	1	0	0	0	0	1	1	1	1	1	1	0	0
0	1	1	0	0	0	1	0	1	1	0	0	0	0	1
0	1	1	0	0	1	0	1	1	0	1	1	0	1	2
0	1	1	0	0	1	1	1	1	1	1	0	0	1	3
0	1	1	0	1	0	0	0	1	1	0	0	1	1	4
0	1	1	0	1	0	1	1	0	1	1	0	1	1	5
0	1	1	0	1	1	0	0	0	1	1	1	1	1	6
0	1	1	0	1	1	1	1	1	1	0	0	0	0	7
0	1	1	1	0	0	0	1	1	1	1	1	1	1	8
0	1	1	1	0	0	1	1	1	1	0	0	1	1	9
0	1	1	1	0	1	0	0	0	0	0	0	0	0	Blank
0	1	1	1	0	1	1	0	0	0	0	0	0	0	Blank
0	1	1	1	1	0	0	0	0	0	0	0	0	0	Blank
0	1	1	1	1	0	1	0	0	0	0	0	0	0	Blank
0	1	1	1	1	1	0	0	0	0	0	0	0	0	Blank
0	1	1	1	1	1	1	0	0	0	0	0	0	0	Blank
1	↑	1	X	X	X	X				*				*

X ≡ Don't Care * Depends on BCD code previously applied when LE = 0

Note: Display is blank for all illegal input codes (BCD > 1001).

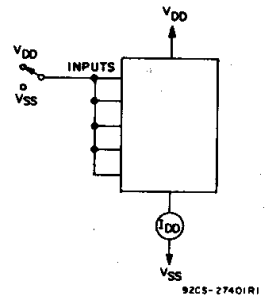


Fig. 9 – Quiescent device current.

TEST CIRCUITS

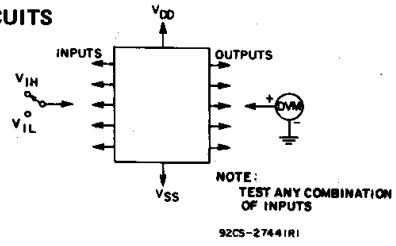


Fig. 10 – Input voltage.

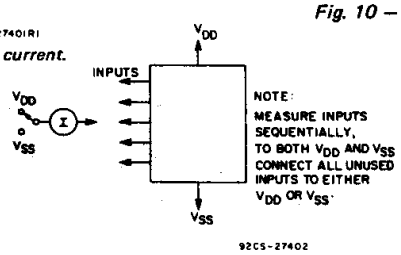
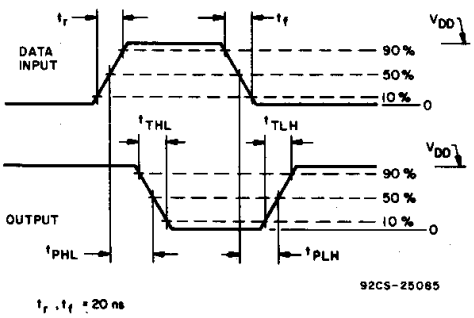


Fig.11 – Input current.



t_r, t_f = 20 ns

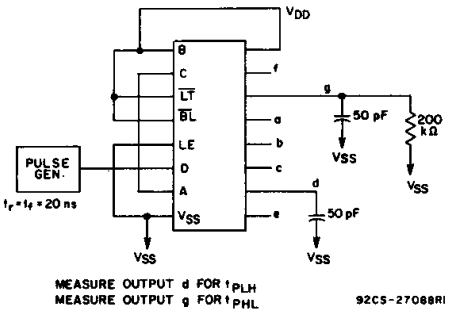


Fig.12 – Data propagation delay.

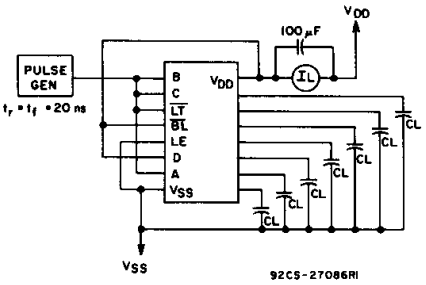
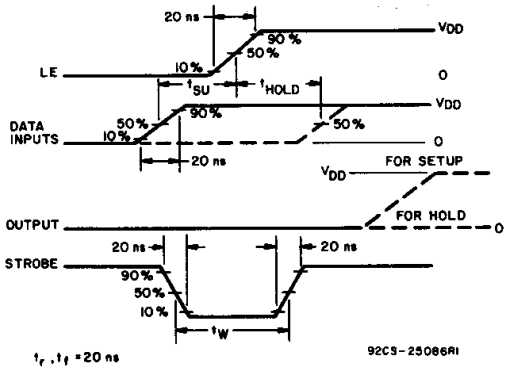


Fig. 13 – Dynamic power dissipation.

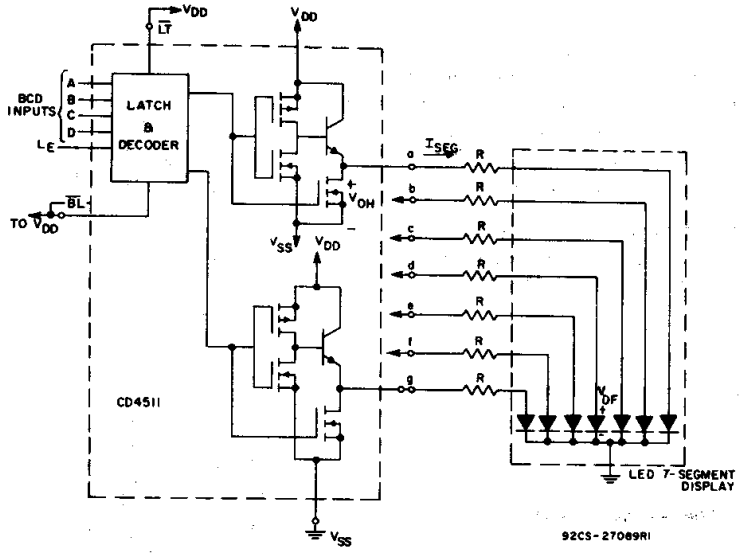


t_r, t_f = 20 ns

Fig. 14 – Dynamic waveforms.

APPLICATIONS

Interfacing with Various Displays

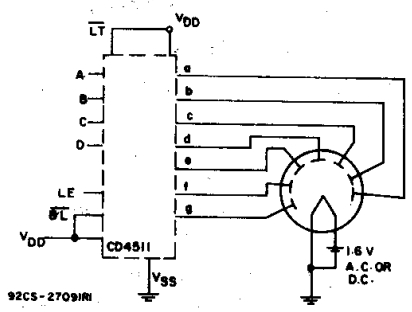


Duty Cycle = 100%

$I_{SEG} = I_{DIODE_{AVG.}}$ = 20 mA at Luminous Intensity/Segment = 250 microcandles

$$R = \frac{V_{OH} - V_{DF}}{I_{SEG}}$$

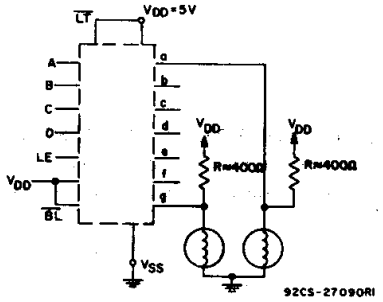
Fig. 15 - Driving common-cathode 7-segment LED displays (example Hewlet-Packard 5082-7740).



A medium-brightness intensity display can be obtained with low-voltage fluorescent displays such as the Tung-Sol Digivac S/G** Series.

**Trademark Tung-Sol Division Wagner Electric Co.

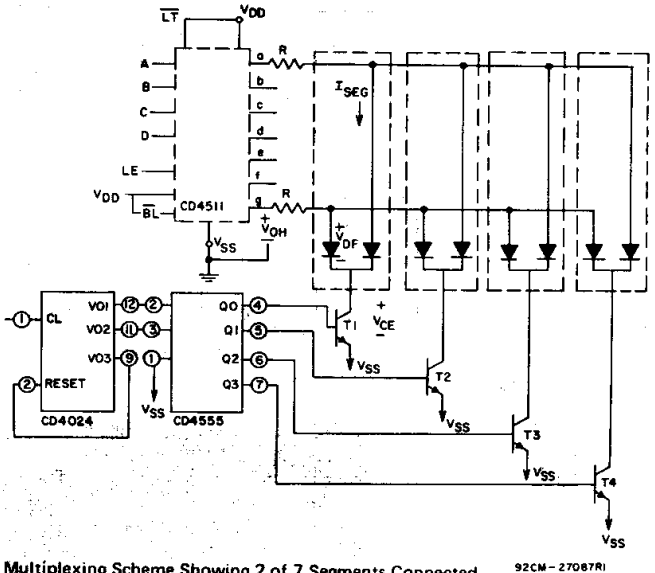
Fig. 16 – Driving low-voltage fluorescent displays.



2 of 7 Segments Shown Connected

Resistors R from V_{DD} to each 7-segment driver output are chosen to keep all Numitron segments slightly on and warm.

Fig. 17 – Driving incandescent displays (RCA Numitron DR2000 series displays).



Multiplexing Scheme Showing 2 of 7 Segments Connected

Transistors T_1–T_4 (RCA-2N3053 or 2N2102) have I_C Max. rating > 7xI_{SEG}

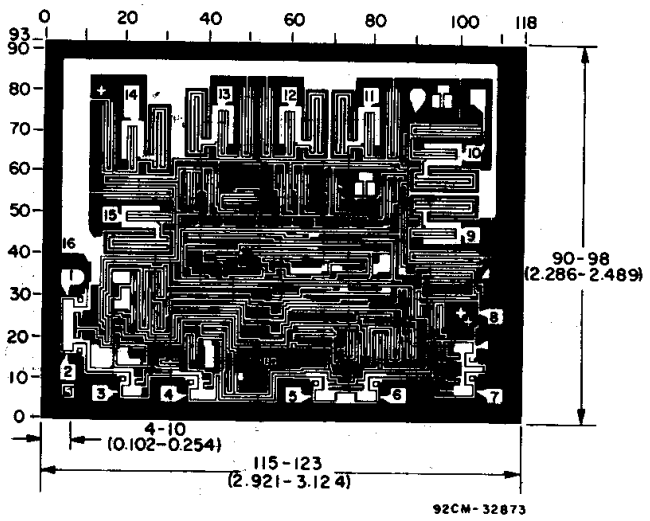
Duty Cycle = 25%

$I_{SEG} = (I_{DIODE_{AVG}}) \times 4$

$$R = \frac{(V_{OH} - V_{DF} - V_{CE})}{I_{SEG}}$$

All unused inputs on CD4555 are connected to V_{DD} or V_{SS}.

Fig. 18 – Multiplexing with common-cathode 7-segment LED displays (example Hewlet-Packard 5082-7404 4 character display or 4 discrete Monosanto Man 3 displays).



Dimensions and pad layout for CD4511B chip.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third–party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Mailing Address:

Texas Instruments
Post Office Box 655303
Dallas, Texas 75265

CD4511B, CMOS BCD-to-7-Segment LED Latch Decoder Drivers

DEVICE STATUS: **ACTIVE**

PARAMETER NAME	CD4511B
Voltage Nodes (V)	5, 10, 15

FEATURES

Back to Top

- High-output-sourcing capability.....up to 25 mA
- Input latches for BCD Code storage
- Lamp Test and Blanking capability
- 7-segment outputs blanked for BCD input codes > 1001
- 100% tested for quiescent current at 20 V
- Max. input current of 1 uA at 18 V, over full package-temperature range, 100 nA at 18 V and 25°C
- 5-V, 10-V, and 15-V parametric ratings
- Applications
  - Driving common-cathode LED displays
  - Multiplexing with common-cathode LED displays
  - Driving incandescent displays
  - Driving low-voltage fluorescent displays

DESCRIPTION

Back to Top

CD4511B types are BCD-to-7-segment latch decoder drivers constructed with CMOS logic and n-p-n bipolar transistor output devices on a single monolithic structure. These devices combine the low quiescent power dissipation and high noise immunity features of RCA CMOS with n-p-n bipolar output transistors capable of sourcing up to 25 MA. This capability allows the CD4511B types to drive LED's and other displays directly.

Lamp Test (LT)\, Blanking (BL)\, and Latch Enable or Strobe inputs are provided to test the display, shut off or intensity-modulate it, and store or strobe a BCD code, respectively. Several different signals may be multiplexed and displayed when external multiplexing circuitry is used. The CD4511B is supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline package (NSR suffix), and in chip form (H suffix).

These devices are similar to the type MC14511.

TECHNICAL RESOURCES

Back to Top

To view the following documents, Acrobat Reader 4.0 is required.

To download a document to your hard drive, right-click on the link and choose 'Save'.

DATASHEET

Back to Top

Full datasheet in Acrobat PDF: cd4511b.pdf (236 KB,Rev.A) (Updated: 03/18/2002)

APPLICATION NOTES

Back to Top

View Application Reports for Digital Logic

- Evaluation of Nickel/Palladium/Gold-Finished Surface-Mount Integrated Circuits (SZZA026 - Updated: 06/20/2001)

RELATED DOCUMENTS

Back to Top

- Advanced Bus Interface Logic Selection Guide (SCYT126, 448 KB - Updated: 01/09/2001)
- Documentation Rules (SAP) And Ordering Information (Rev. B) (SZZU001B, 13 KB - Updated: 05/06/1999)
- Logic Selection Guide First Half 2002 (Rev. Q) (SDYU001Q, 3368 KB - Updated: 12/17/2001)
- MicroStar Junior BGA Design Summary (SCET004, 167 KB - Updated: 07/28/2000)
- More Power In Less Space - Technical Article (Rev. A) (SCAU001A, 850 KB - Updated: 03/01/1996)
- Overview of IEEE Std 91-1984, Explanation of Logic Symbols Training Booklet (Rev. A) (SDYZ001A, 138 KB - Updated: 07/01/1996)

SAMPLES

Back to Top

ORDERABLE DEVICE	PACKAGE	PINS	TEMP (°C)	STATUS	DSCC NUMBER	SAMPLES
CD4511BE	N	16	-55 TO 125	ACTIVE		Request Samples
CD4511BNSR	NS	16	-55 TO 125	ACTIVE		Request Samples
CD4511BPWR	PW	16	-55 TO 125	ACTIVE		Request Samples

PRICING/AVAILABILITY/PKG

Back to Top

ORDERABLE DEVICE	PACKAGE	PINS	TEMP (°C)	STATUS	BUDGETARY PRICE US$/UNIT QTY=1000+	PACK QTY	DSCC NUMBER	PRICING/AVAILABILITY/PKG
CD4511BE	N	16	-55 TO 125	ACTIVE	0.35	25		Check stock or order
CD4511BF	J	16	-55 TO 125	ACTIVE	2.87	1		Check stock or order
CD4511BF3A	J	16	-55 TO 125	ACTIVE	3.40	1		Check stock or order
CD4511BNSR	NS	16	-55 TO 125	ACTIVE	0.60	2000		Check stock or order
CD4511BPW	PW	16	-55 TO 125	OBSOLETE				
CD4511BPWR	PW	16	-55 TO 125	ACTIVE	0.35	2000		Check stock or order

Table Data Updated on: 5/1/2002